Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/540,324	LEE, JONG-CHO	
Examiner	Art Unit	
M. Alexandra Elve	1725	

SEARCHED					
Class	Subclass	Date	Examiner		
219	69.12	6/25/2007	MAE		
219	69.11	6/25/2007	MAE		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
·	DATE	EXMR	
US OCR, US PAT, US PG, Derwent, JPO, EPO	6/25/2007	MAE	
Inventor search (PALM)	6/25/2007	MAE	
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